Defects in Energy and Electronic Materials: From Experiment to Machine Learning

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Message from the Guest Editors

Dear Colleagues,

Future applications, including the Internet of Things (IoT) require new energy and electronic materials that are in abundance, low cost and environmentally friendly and exhibit high energy density. This will enable the next generation of high-capacity energy storage and energy harvesting systems. The miniaturization of devices necessitates a fundamental understanding of material defect processes more than ever. In this respect, advanced computational techniques and their synergy with experiments are required to gain a deeper understanding and better control at nanoscale dimensions. This Special Issue will focus on defect processes in energy and electronic materials with a particular focus on advanced computational works and the prospects for machine learning and intelligent approaches.

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Special Issue

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Message from the Editor-in-Chief

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